

**Search Notes**

Application/Control No.

10/722,991

Examiner

Toan M. Le

Applicant(s)/Patent under  
Reexamination

HOYTE, SCOTT MORDIN

Art Unit

2863

**SEARCHED**

Class	Subclass	Date	Examiner
702	65	8/4/2005	TL
324	207.16	8/4/2005	TL
324	207.11	8/4/2005	TL
324	207.26	8/4/2005	TL
324	699	8/4/2005	TL
324	716	8/4/2005	TL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
702	65	8/4/2005	TL
324	207.16	8/4/2005	TL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Gap Determination, Impedance, Material Property	8/4/2005	TL
Gap, Eddy Current Proximity Sensor Probe	8/4/2005	TL
Proximity Probe	8/4/2005	TL
Data Structure Target Conductivity Material Composition Complex Property Transducer Interpolation	8/4/2005	TL
East, Web, and NPL search <i>Interfer. and search history print out</i>		